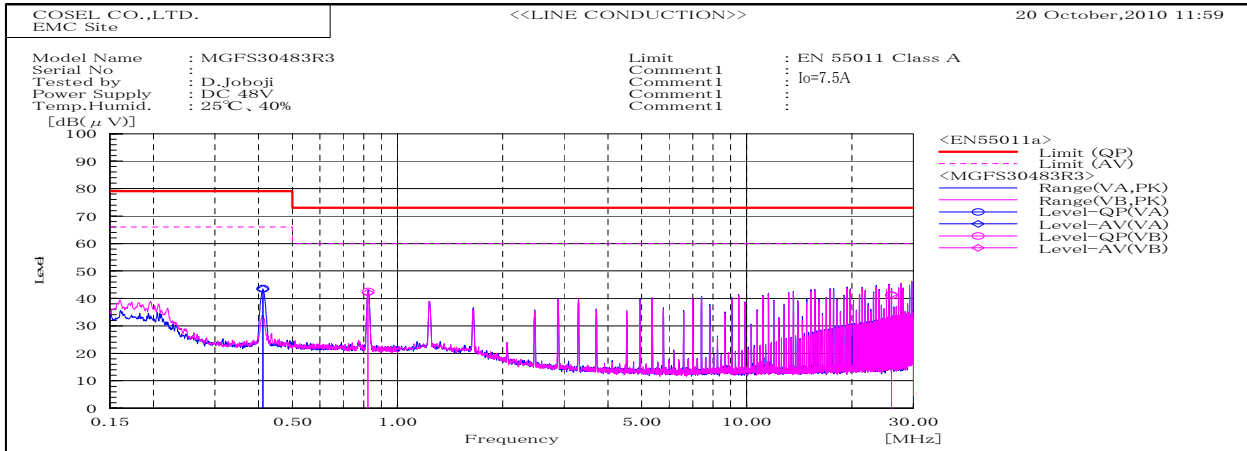
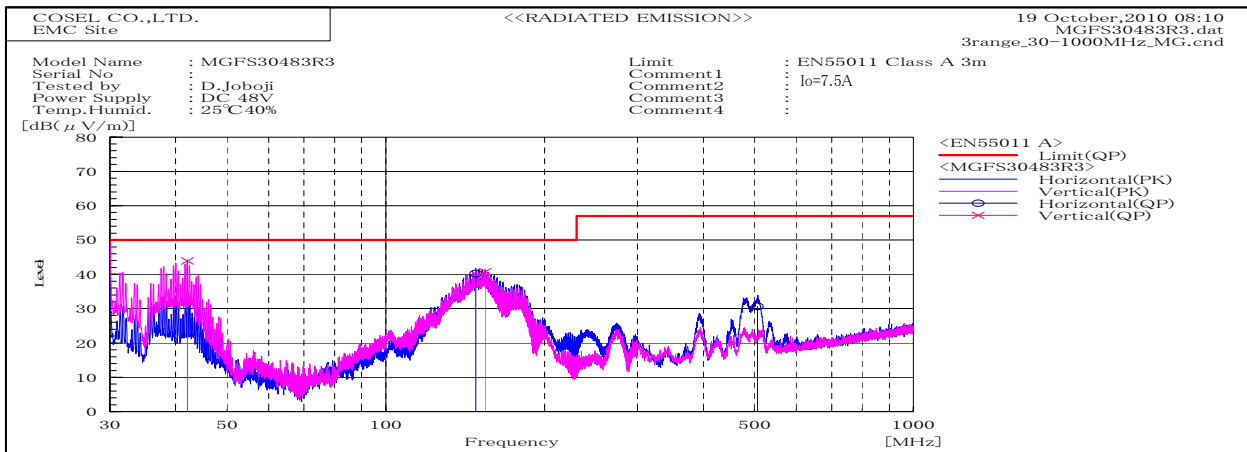


DATA SHEET		Date	20-Oct-10
Model	MGFS30483R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Joboji



Frequency MHz	Ham	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.41152		VA	33.5	33.3	10.1	43.6	43.4	79	66	35.4	22.6	Pass	
0.82308		VB	32.5	32	10	42.5	42	73	60	30.5	18	Pass	
25.95515		VB	30.1	30.4	11	41.1	41.4	73	60	31.9	18.6	Pass	

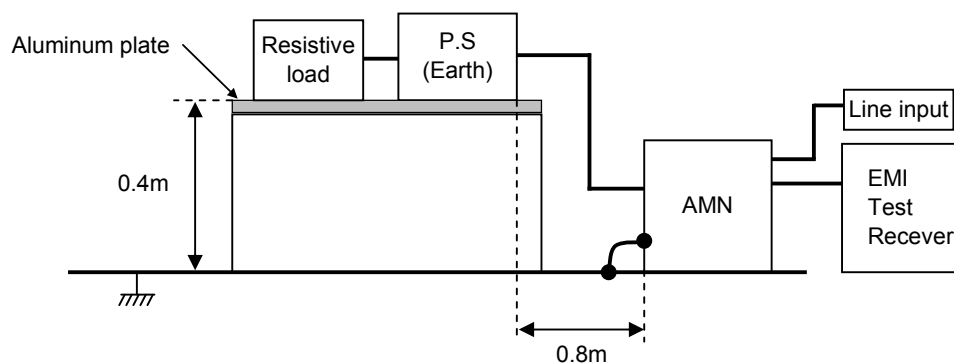


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
42.069	V	Stable	63.5	-19.6		43.9		50	6.1	101	95	
148.085	H	Stable	60.5	-20.2		40.3		50	9.7	136	132	
154.272	V	Stable	61.2	-20.4		40.8		50	9.2	139	242	
506.514	H	Stable	42.5	-11.9		30.6		57	26.4	155	359	

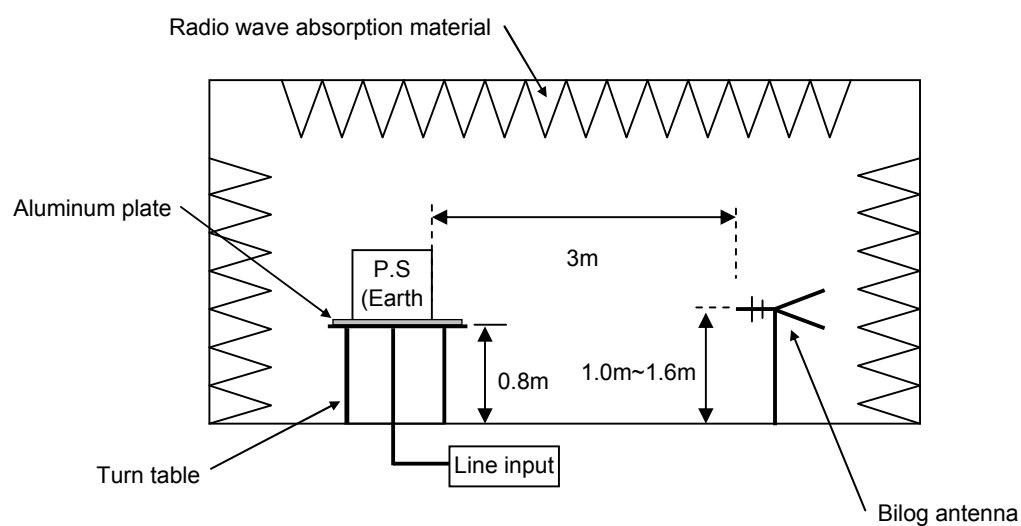
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

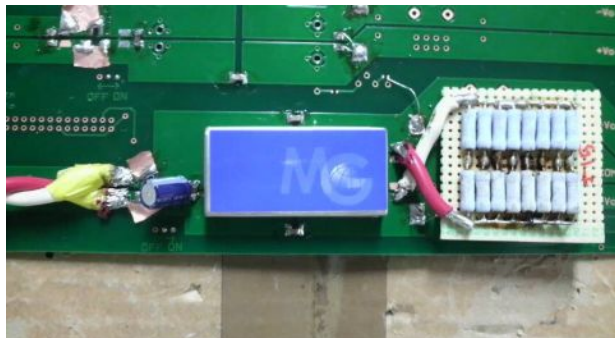


Conditions

Test : EMI
 Model Name : MGFS3048□□/MGFW3048□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

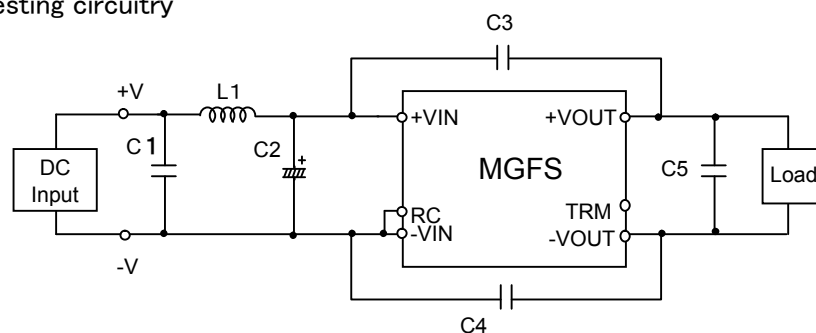


Fig.1 Testing circuitry 1

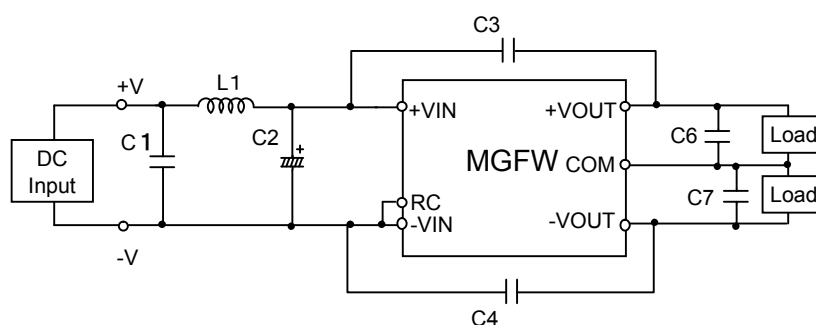


Fig.2 Testing circuitry 2

L1	: 4.7uH	CI8C-4R7	(KORIN ELECTRONICS)
C1	: 100V	2.2 μ F	Ceramic Capacitor
C2	: 80V	47 μ F	Electrolytic Capacitor
C3,C4	: 2kV	1000pF	Ceramic Capacitor
C5,C6,C7	: 25V	22 μ F	Ceramic Capacitor